GENERAL-PURPOSE SYSTEM SOLUTION / FFP (FAR FIELD PATTERN) MEASUREMENT SYSTEM

FFP MEASUREMENT SYSTEM

FFP measurement and analysis system in combination with dedicated FFP measurement optics & image processing method.

FFP (far field pattern) measurement system is for measuring FFP (far field pattern) of semiconductor lasers, optical fibers, optical waveguides, various optical modules and so on. With dedicated f- θ lens optics and image processing method, it can be applied to FFP measurement, radiation angle distribution measurement, emission N.A. measurement and analysis of various optical devices.

[Features]

- $\bigcirc M\text{-}Scope \ type \ F, \ FFP \ measurement \ optics$
- Quick and easy measurement by dedicated f-θ lens optics and image processing method.
 Long working distance design with the working distance of approx. 6±0.8mm.
- ○Possible to measure in 400nm to 1700nm wavelength range by selecting detector.
- Optical beam analysis module **AP013**, specially designed high-functional image processing software for optical beam profile analysis
 - All-in-one package of PC, optical beam analysis software, detector driver, correction data.
 - High-performance image processing software for optical beam profile measurement **Optimetrics BA Standard** is pre-installed.

[Standard component]

- $\bigcirc \mathsf{FFP}$ measurement optics selection
- 650~1700nm:**M-Scope type F**
- 400-650nm:M-Scope type F/BL
- OAvailable detector selection
 - 400-1100nm : Hi-resolution CMOS detector ISA071/ISA071GL
 - 950-1700nm : InGaAs high sensitivity NIR detector ISA041H2
 - 400~1700nm : InGaAs high resolution NIR detector ISA041HRA
- Regarding the measurement angle coverage and pixel resolution during FFP measurement by the detector used, please refer to P50 [Detector selection and FFP measurement specifications]
- Optical beam analysis module AP013
- PC for image processing, optical beam analysis software **Optometrics BA Standard**, detector driver, calibration data, USB key Accessories
 - Cables, instruction manuals, etc.

[Option]

- OND filter
 - Visible (400~700nm): NDF-5 (5 types per set)
- NIR (700~1100nm): NDF NIR-5 (5 types per set)
- IR (1310~1550nm): NDF IR-5 (5 types per set)

Optics bench

- Optics bench for fiber measurement with manual stages
- Vertical setting optics bench

• HIGH RESOLUTION FFP MEASUREMENT OPTICS FOR IR RANGE

High-resolution IR FFP measurement system exclusively for the 1310~1550 nm spectral range

[Standard component]	Available detec	tor, angle coverage, pixel re		
OHigh resolution FFP measurement	Detector	VGA-type InGaAs NIR detec	ctor ISA041VH	
optics for IR M-Scope type FHR	Spectral range	950~1700nm		
○VGA-type InGaAs NIR detector	Total pixels	640×512 pixels		
Ontical beam analysis module	Pixels pitch	20µm sq.		
	Meas. angle /	Meas. angle	Pixel resolution	
[Ontion]	pixel resolution	±32°(V)×±25.6°(H)	0.1°	
OIR ND filter, optics bench, etc.	*Pixel resolution: Measured angle equivalent to the detector pixel calculated from measured angle range and sensor pitch of the detector.			

[Component selection of FFP measurement system]



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